


<b>Search Notes</b> 	<b>Application/Control No.</b> 110784446	<b>Applicant(s)/Patent Under Reexamination</b> EYAL, AVIV
	<b>Examiner</b> Krisna Lim	<b>Art Unit</b> 2453

SEARCHED			
Class	Subclass	Date	Examiner
709	231, 245, 223	2/4/09	kl
707	10, 223	2/4/09	kl
345	327	2/4/09	kl

SEARCH NOTES			
Search Notes		Date	Examiner
Inventor		2/4/09	kl

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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